EV218282061

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Priority Application Serial No. 10/057,711
Priority Filing Date ..... January 24, 2002
Inventor ..... Warren M. Farnworth et al.
Assignee ..... Micron Technology, Inc.
Priority Group Art Unit 2829
Priority Examiner ..... R. Kobert
Attorney's Docket No. MI22-2379
TITLE: Method and Apparatus for Testing Semiconductor Circuitry for Operability and Method of Forming Apparatus for Testing Semiconductor Circuitry for Operability

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Commissioner for Patents
Washington, D. C. 20231

SUBSTITUTE DRAWING REQUEST

Please enter the enclosed substitute formal drawings in the above-referenced application in place of drawings originally filed. The content of the drawings are identical to those now on file in this application.

Acknowledgment of receipt of the formal drawings and their acceptance into the file is requested.

Respectfully submitted,

Date: 7-31-03 By: _____

D. Brent Kenady
Reg. No.: 40,045
CUSTOMER NO. 021567

Enclosures: *10 Sheets of Formal Drawings, Figs. 1-19.*